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sense and simplicity

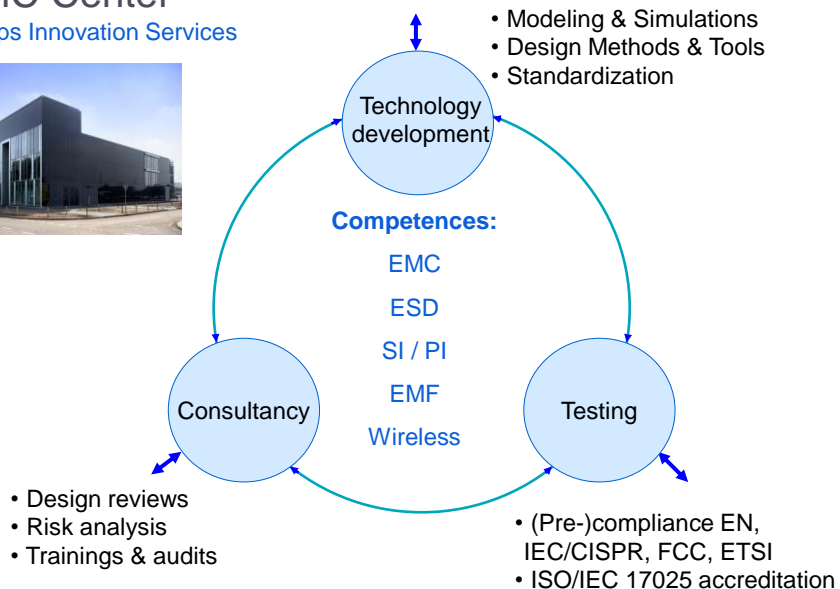
CIGRE working group C4.111 Review of LV and MV compatibility levels for voltage fluctuations *Status*

P.A. Beeckman
Philips Innovation Services & NL member Cigre C4.111
Cigre NSC C4 meeting Eindhoven; June 7, 2013

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NOTES

1. Remark: This presentation constitutes a personal interim status report; it is not the final & formal conclusion of the Cigre C4.111 working group. The final report with recommendations is expected by December 2013
2. Scope: The flicker aspects in this presentation are limited to flicker resulting from voltage fluctuations (flicker in the sense of IEC 61000-4-15). Hence no stroboscopic effects are considered!

Content

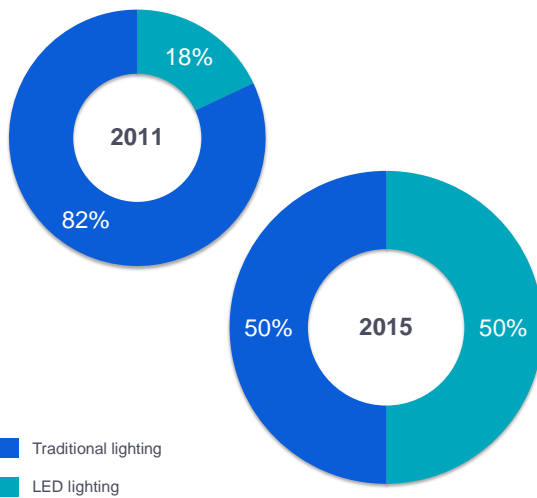
- Introduction
- Standardization
- Flicker immunity tests
- Summary

Background & scope

INTRODUCTION

The LED revolution

Digital lighting is transforming the entire landscape*



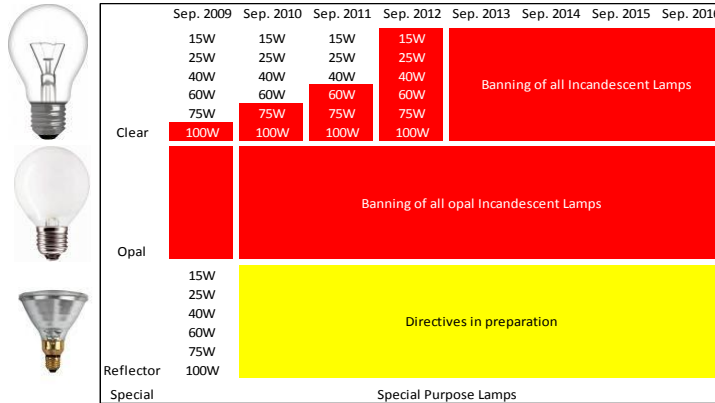
*Source: Philips Lighting global market study 2009, updated for 2010



Oliveira Bridge, Sao Paulo, Brazil 6

Banning of Incandescent lamps

EU example



Significant reduction of the electrical usage of lighting equipment during the next 10 years (10% → 4% → 2%)

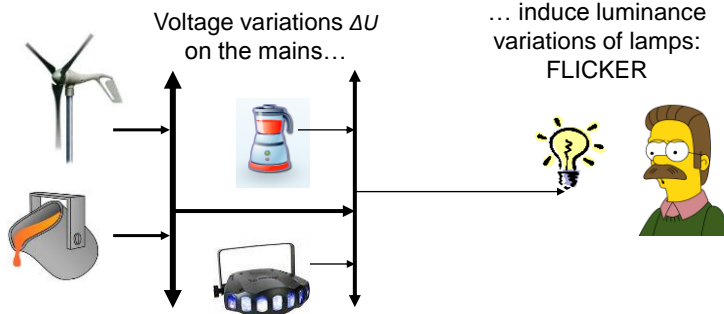
...results into various EMC/PQ issues associated with lighting applications

- Harmonics, power factor
- Inrush currents
- Voltage fluctuations & flicker
- Frequency region 'gap' in EMC standards (2 kHz – 9/150 kHz)
- ...

Status

STANDARDIZATION

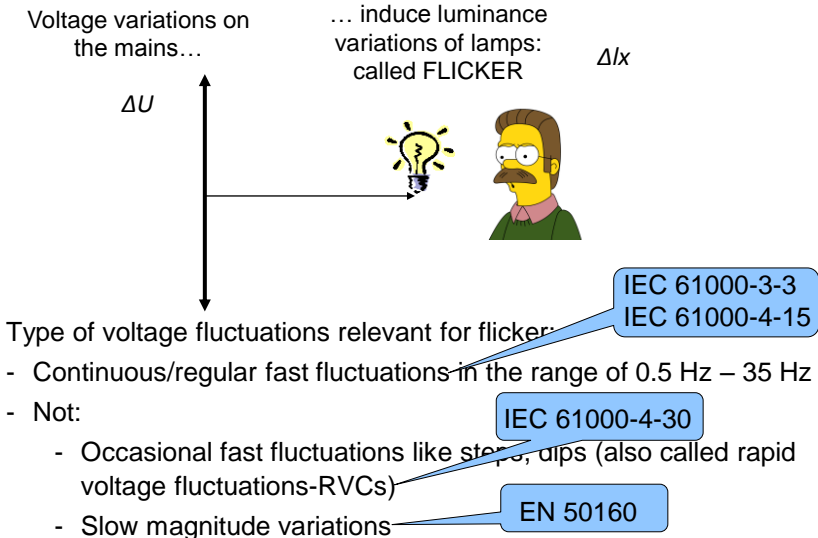
Flicker induced by equipment connected to the grid



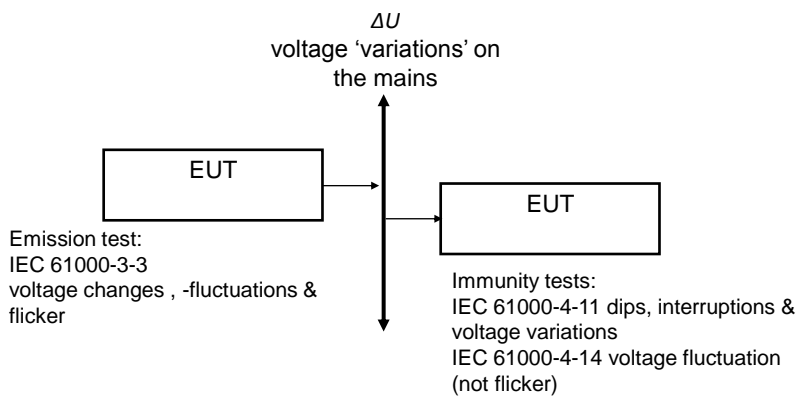
Varying & switching sources & loads

- heavy industry on the MV-grid
- appliances on the LV-grid

Type of voltage variations & standards

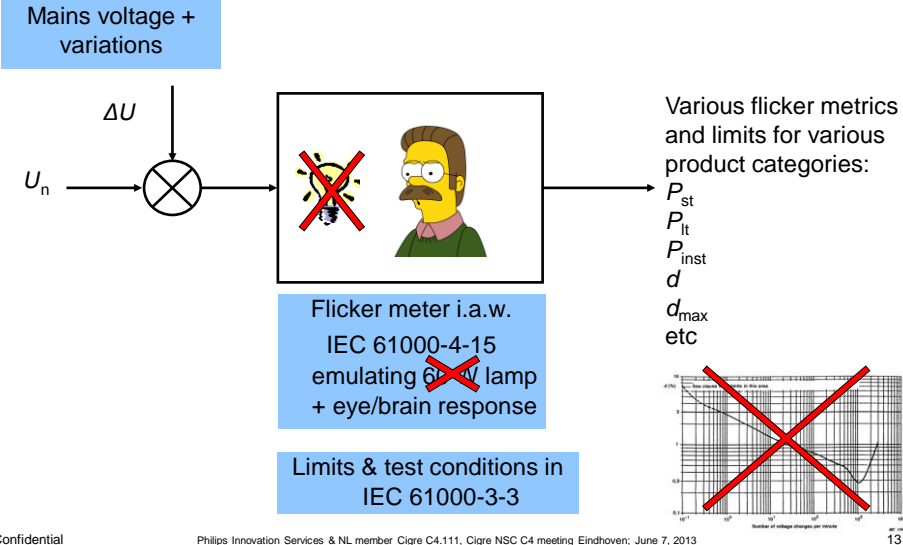


Voltage fluctuations: emission & immunity

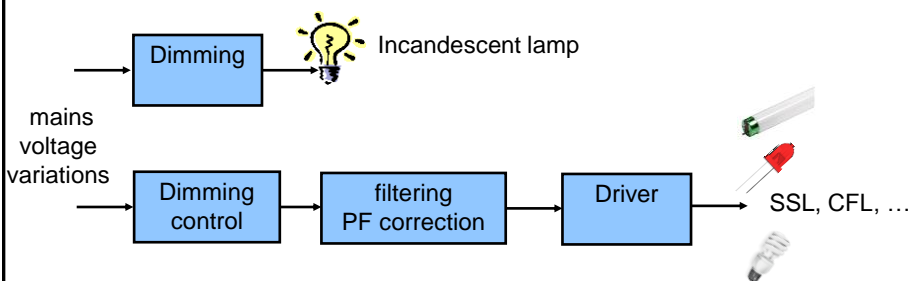


Incandescent lamp is considered the most sensitive equipment apparatus connected to a LV-mains, therefore no immunity test as counterpart of IEC 61000-3-3 exists

Flicker meter: emulates perception of flicker of a 60 W incandescent lamp = reference



Flicker influence quantities



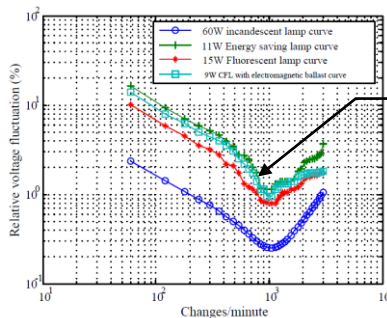
Future lighting equipment: much more flicker influence quantities involved (compared to incandescent) due to diversity of

- lamp types
- driver- and dimming/control-, PF-correction/filtering-technologies

New flicker requirements possible/needed?

More relaxed requirement (allowance of higher voltage fluctuations) possible?:

- Other, than lighting equipment may experience malfunction
- New lamp technologies and driver/control topologies and dimming (installed base!) may be also more sensitive to flicker



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IEC SC 77A & CIGRE C4.111



C4.111 → SC 77A/WG2

- IEC SC77A requested CIGRE¹⁾ for advice
- CIGRE task force C4.111
 - has reviewed the adequacy of the present IEC flicker meter & limits
 - will provide recommendations to IEC SC77A by end of 2013
 - anticipated recommendations:
 - no or minor change of the flicker limit line
 - development of a flicker-immunity test for lighting equipment
- Subsequently IEC SC77A/WG2 might start maintenance of the associated standards
 - IEC 61000-3-3 = the 'IEC-flicker standard' (testing level of induced of voltage fluctuations)
 - IEC 61000-4-15 = the IEC flicker meter specification
 - also WG8 (responsible for compatibility levels) might be tasked

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CIGRE C4.111 activities



- TOR, see <http://c4.cigre.org/WG-Area/WG-C4.111-Review-of-LV-and-MV-Compatibility-Levels-for-Voltage-Fluctuation>
- Convenor prof Mark Halpin
- Meetings:
 - June, November 2011
 - February, June, December 2012
 - March, July, December 2013
- Work left: to collate inputs and edit the final report (due end of 2013)

CIGRE questionnaire issued in August 2011

- Q: What are consequences if the flicker curve would be raised 1.25 – 3 times
- 32 responses received from utilities, equipment- and lighting manufacturers
- Results categorized: support, no support, etc
- Results tend in one direction, i.e. no major change of the flicker curve
- Reasons
 - Incandescent/ halogen lamps are still in operation for several years
 - Fear of raise of complaints
- Instead: a real EMC approach needed by introducing an immunity test as a counterpart of the flicker emission test
- Results have been formally submitted to IEC (2012-Q1) as an intermediate result

IEC SC 77A & IEC TC34

- October 3012: Mr. Deter member of the joint-TC34/SC77A-forum pro-actively initiated the development of voltage-fluctuation immunity standard for lighting equipment
- This informal request is to be formalized i.a.w. the IEC procedures
- Goal is to amend the EMC immunity standard IEC 61547 for lighting equipment
- Work to be performed by a PT & MT1 of IEC TC34
- Liaison of SC77A-WG2 member Johan Wijntjens (Philips)
- PInS EMC Center is setting up a demonstrator for an immunity test

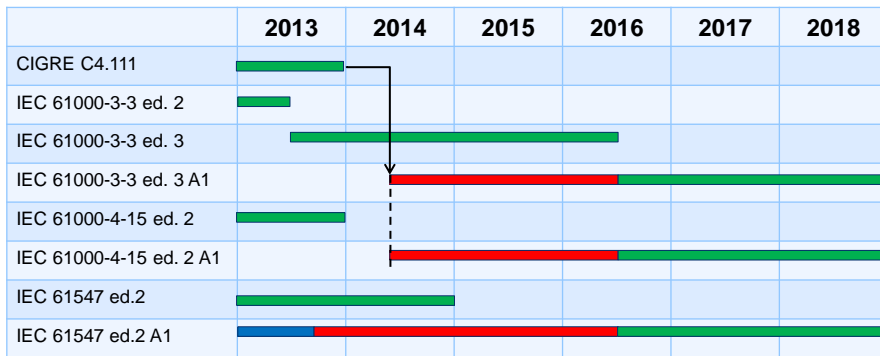


SC 77A/WG2



TC34/MT1

Overview/timeline IEC-flicker developments



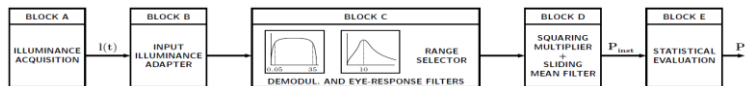
= lifetime/stability period

= IEC project

= preparatory work

PIInS project: development of an objective IEC-flicker immunity test for lighting equipment

- Goal: tool to support IEC TC34 standardization
- h/w for test
 - Chroma 61602
 - 33250A waveform generator Agilent
 - 50 Hz AFG R&S
 - Illuminance sensor
- control & data acquisition via Matlab
- Investigation of various flicker metrics for various types of lamps



EU/Cenelec actions



- EC Mandate M/519 issued February 2013:
http://ec.europa.eu/enterprise/policies/european-standards/standardisation-requests/index_en.htm
- European standards for flicker and stroboscopic effects to be enhanced or to be developed!

FLICKER IMMUNITY TESTS

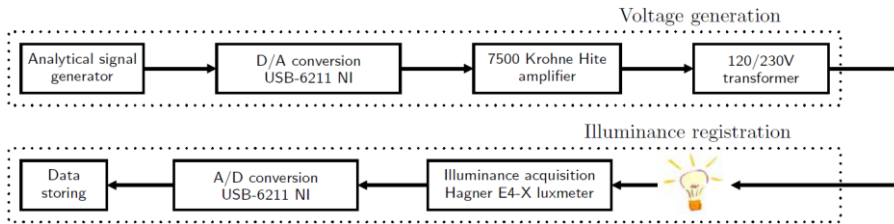
Quantitative tests @ Bilbao University

- Aug/Sep 2011: a limited # of samples of using various types of lamps, different driver technologies & different types of dimmers
- Hypothesis: future lamp technologies may be as flicker sensitive as incandescent lamps = justification for not changing the flicker meter/limits

Lamp type	Power	Brightness control	Remark
Incandescent	60 W		
LED	8 W	analog	optimized for LE dimmers
LED	12 W	digital	LE and TE dimmable
CFL	12 W	analog	LE and TE dimmable
CFL	11 W	supposedly analog	LE and TE dimmable with dimmer detection

Manufacturer	Technology
Busch-Jaeger	Leading Edge (LE)
Merten	Trailing Edge (TE)

Quantitative tests @ Bilbao University



Gain curves(f_m): (relative illuminance variation/relative voltage fluctuation)=

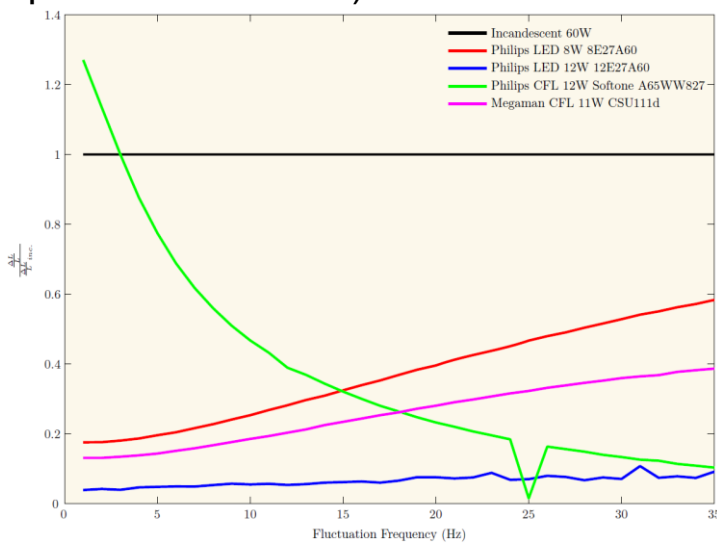
$$gain = \frac{\Delta L / L}{\Delta V / V}$$

Results shown in terms of normalized gain curves
(relative to incandescent lamp)

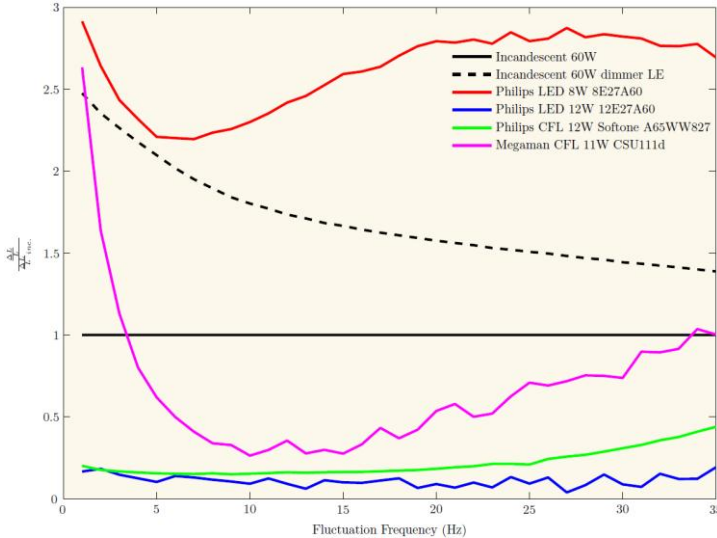
$$normalised\ gain = \frac{\Delta L_{EUT} / L_{EUT}}{\Delta L_{INC} / V_{INC}}$$

=1 =reference =incandescent lamp
>1 more sensitive
<1 less sensitive

Quantitative tests @ Bilbao University: results (lamps without dimmer)



Quantitative tests @ Bilbao University: results (lamps with dimmer; 15 % dimming)



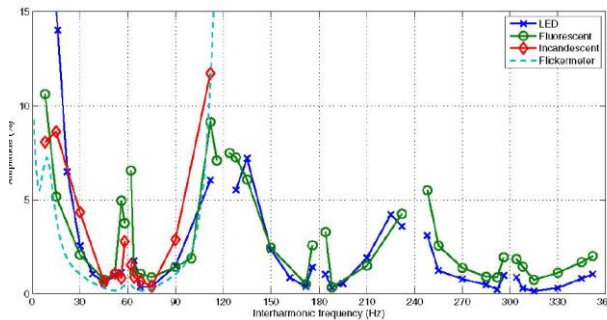
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Flicker immunity against 'high-frequency' variations

- CFL & LED lighting may be sensitive beyond the modulation frequencies of the flicker curve
- Due to diode bridge, inter-modulation frequencies result from intentional signals in addition to the mains frequency e.g. PLT, mains signalling



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Summary

(this is not the final & formal conclusion of C4.111!)

- Flicker sensitivity of lighting applications has become much more diverse (either more or less sensitive than the 60 W incandescent lamp)
- Technical influence quantities for flicker sensitivity are:
 - Lighting technology
 - Electronics (driver/PFC/filter) topology
 - Dimming technology
 - Dimming level
 - The reference impedance
 - Frequency of modulation
- New flicker compatibility-levels and immunity test will be defined within IEC standards in the coming years

Acknowledgement

This work is supported by the Eniac Joint Undertaking project Enlight:
Energy efficient and intelligent lighting systems



